

AMENDMENT TRANSMITTAL LETTER (Large Entity)

Applicant(s): Sung-min YIM et al.

Docket No.

SEC.813

Serial No.
09/955,310Filing Date
19 September 2001Examiner
Emily Y. CHANGroup Art Unit
2829

Invention: APPARATUS AND METHOD FOR MEASURING ELECTRICAL CHARACTERISTICS OF A SEMICONDUCTOR ELEMENT IN A PACKAGED SEMICONDUCTOR DEVICE

DEC 01 2003

TO THE COMMISSIONER FOR PATENTS:

Transmitted herewith is an amendment in the above-identified application.

The fee has been calculated and is transmitted as shown below.

CLAIMS AS AMENDED

	CLAIMS REMAINING AFTER AMENDMENT	HIGHEST # PREV. PAID FOR	NUMBER EXTRA CLAIMS PRESENT	RATE	ADDITIONAL FEE
TOTAL CLAIMS	19 -	20 =	0	x \$18.00	\$0.00
INDEP. CLAIMS	4 -	4 =	0	x \$86.00	\$0.00
Multiple Dependent Claims (check if applicable) <input type="checkbox"/>					\$0.00
TOTAL ADDITIONAL FEE FOR THIS AMENDMENT					\$0.00

No additional fee is required for amendment.

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- Any additional filing fees required under 37 C.F.R. 1.16.
- Any patent application processing fees under 37 CFR 1.17.

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Dated: 1 December 2003

KENNETH D. SPRINGER
REG. NO.: 39,843VOLENTINE FRANCOS, PLLC
12200 SUNRISE VALLEY DRIVE, SUITE 150
RESTON, VA 20191

TEL. NO.: (703) 715-0870

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re PATENT APPLICATION of:

Sung-min YIM et al.

Group Art Unit: 2829

Serial No.: 09/955,310

Examiner: Emily Y. CHAN

Filed: 19 September 2001

APPARATUS AND METHOD FOR
MEASURING ELECTRICAL
CHARACTERISTICS OF A
SEMICONDUCTOR ELEMENT IN A
PACKAGED SEMICONDUCTOR
DEVICE

SECOND AMENDMENT UNDER 37 C.F.R. § 1.111

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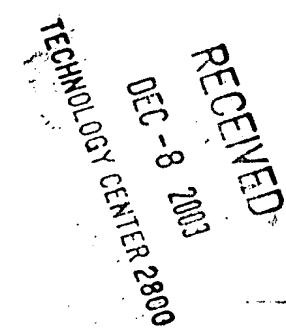
Sir:

In response to the Office Action dated 4 September 2003, the period for response to which extends through 4 December 2003, please amend the above-identified patent application as follows:

Amendments to the Specification begin on page 3 of this paper.

Amendments to the Claims are reflected in the listing of claims which begins on page 4 of this paper.

Amendments to the Drawings begin on page 9 of this paper and include both an attached replacement sheet and an annotated sheet showing changes.



Remarks begin on page 10 of this paper.

An **Appendix** including amended drawing figures is attached following page 21 of this paper.